

Product Summary

$V_{(BR)DSS}$	$R_{DS(on)TYP}$	I_D
40V	4.1m Ω @10V	85A

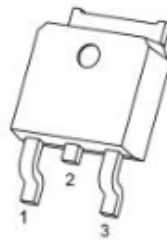
Feature

- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation

Application

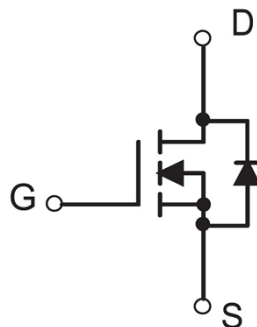
- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply

Package

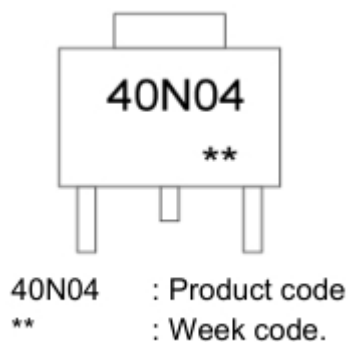


TO-252-2L(G:1 D:2 S:3)

Circuit diagram



Marking



Absolute maximum ratings

(T_a=25°C unless otherwise noted)

Parameter	Symbol	Value	Unit
Drain-Source Voltage	V _{DS}	40	V
Gate-Source Voltage	V _{GS}	±20	V
Drain Current-Continuous	I _D	85	A
Pulsed Drain Current	I _{DM}	340	A
Maximum Power Dissipation	P _D	83	W
Derating factor		0.53	W/°C
Single pulse avalanche energy ^(Note 5)	E _{AS}	750	mJ
Thermal Resistance,Junction-to-Case ^(Note 2)	R _{θJC}	1.8	°C/W
Operating Junction and Storage Temperature Range	T _J , T _{STG}	-55 to 150	°C

Electrical characteristics

($T_A=25^{\circ}\text{C}$, unless otherwise noted)

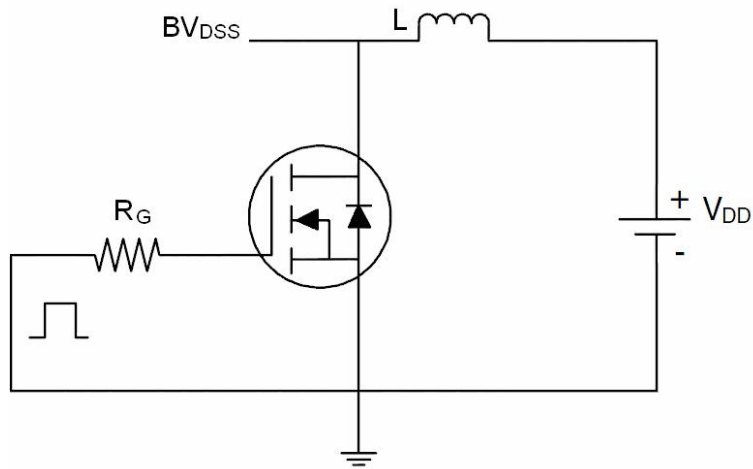
Parameter	Symbol	Test Condition	Min.	Typ.	Max.	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV (BR)DSS	V _{GS} = 0V, I _D =250μA	40	45		V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =40V,V _{GS} = 0V			1	uA
Gate-Body Leakage Current	I _{GSS}	V _{GS} = ±20V , V _{DS} =0V			±100	uA
On Characteristics (Note 3)						
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _D =250μA	1.2	1.6	2.5	V
Drain-Source On-State Resistance ³	R _{DS(on)}	V _{GS} =10V, I _D =20A		4.1	6	mΩ
		V _{GS} =4.5V, I _D =20A		5	7	
Forward Transconductance	g _{FS}	V _{DS} =10V,I _D =20A	15			S
Dynamic Characteristics						
Input Capacitance	C _{iss}	V _{DS} =20V, V _{GS} =0V, f=1MHz			5000	pF
Output Capacitance	C _{OSS}				900	
Reverse Transfer Capacitance	C _{rss}				500	
Switching Characteristics						
Turn-On Delay Time	T _{d(on)}	V _{DD} =20V, R _L =1Ω, V _{GS} =10V, R _G =3Ω		12		nS
Rise Time	T _r			11		
Turn-Off Delay Time	T _{d(off)}			39		
Fall Time	T _f			12		
Total Gate Charge	Q _g	V _{DS} =20V, I _D =20A, V _{GS} =10V		61		pF
Gate-Source Charge	Q _{gs}			15.3		
Gate-Drain Charge	Q _{gd}			14.5		
Diode Characteristics						
Diode Forward Voltage ^(Note 3)	V _{SD}	V _{GS} =0V, I _S =10A			1.2	V
Reverse Recovery Time	t _{rr}	T _J = 25°C, I _F = 20A			45	nS
Reverse Recovery Charge	Q _{rr}	di/dt = 100A/μs ^(Note3)			50	nC

Note:

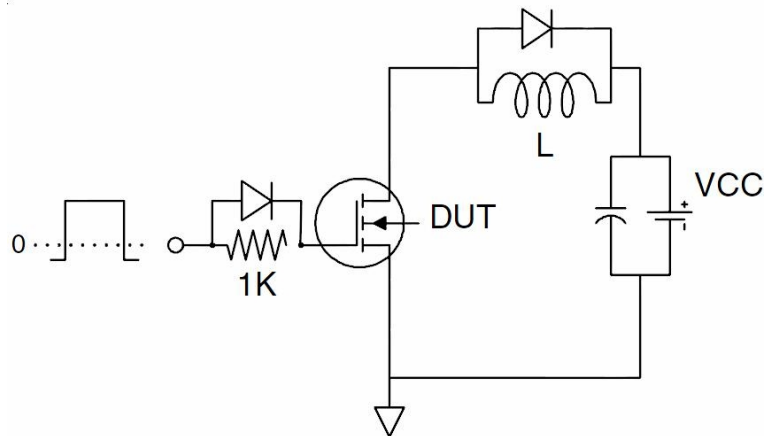
1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board, $t \leq 10$ sec.
3. Pulse Test: Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 2\%$.
4. Guaranteed by design, not subject to production
5. EAS condition: $T_J = 25^{\circ}\text{C}, V_{DD} = 15V, V_G = 10V, L = 0.5mH, R_G = 25\Omega, I_{AS} = 35A$

Test Circuits

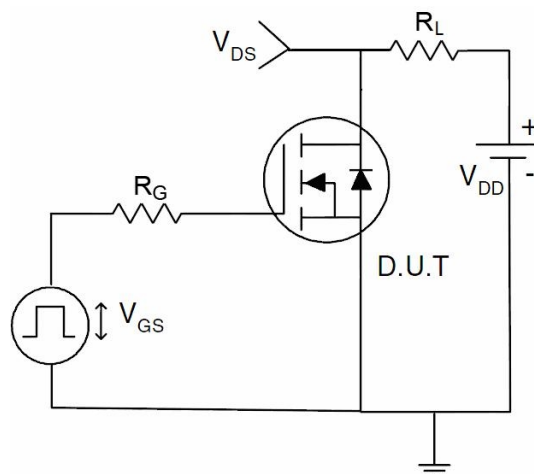
- EAS Test Circuits



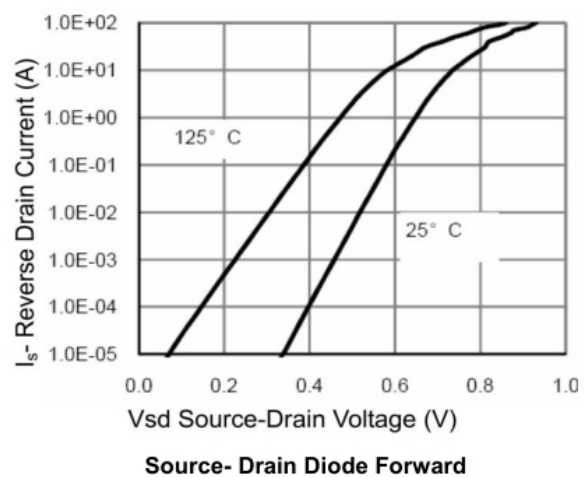
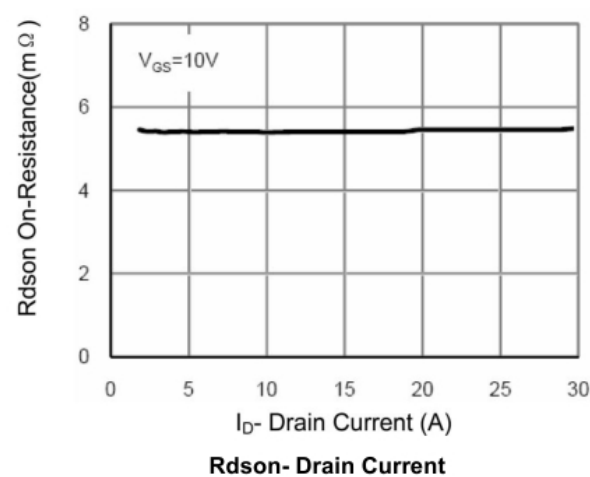
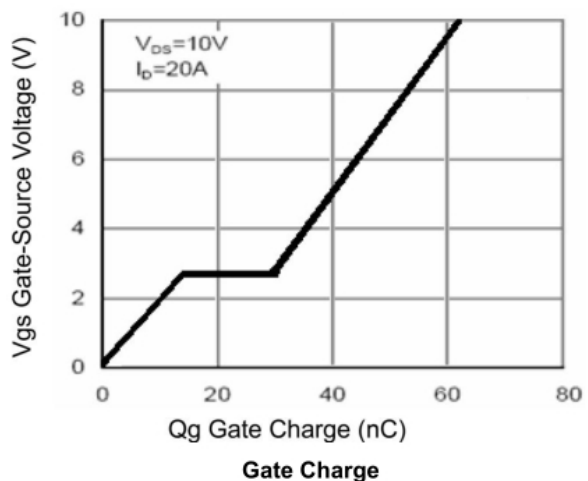
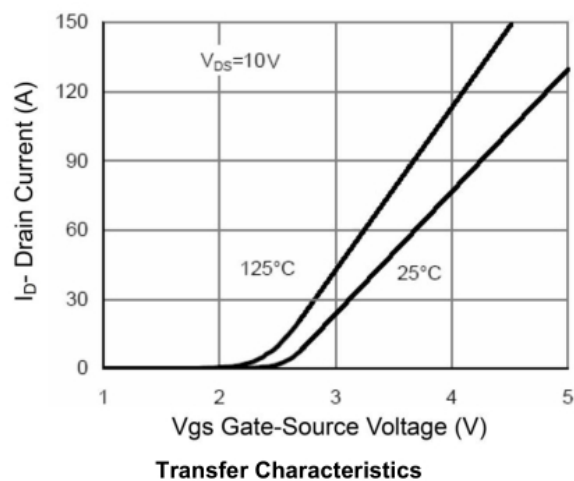
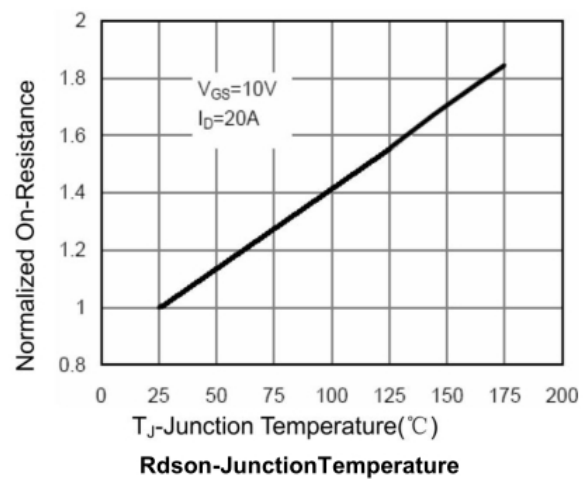
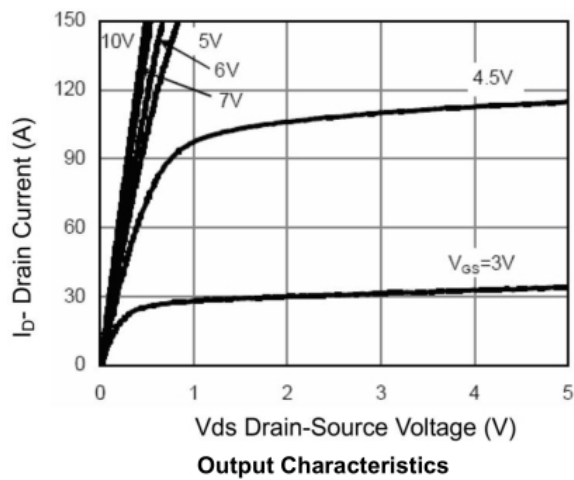
- Gate Charge Test Circuit

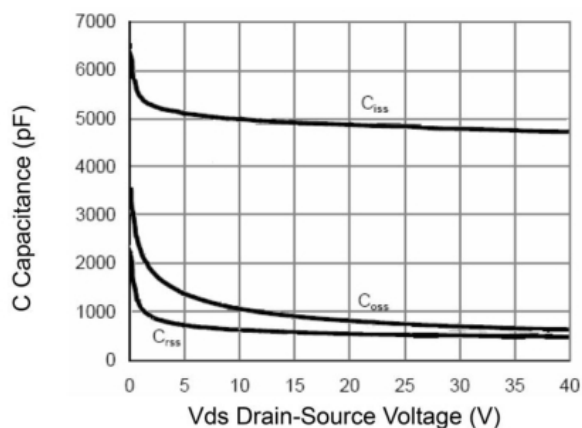


- Switch Time Test Circuit

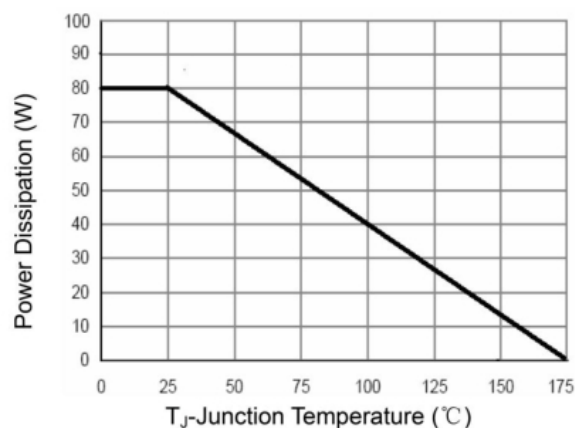


Typical Characteristics

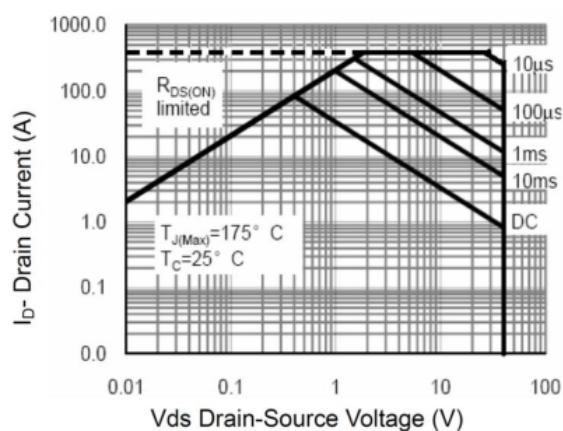




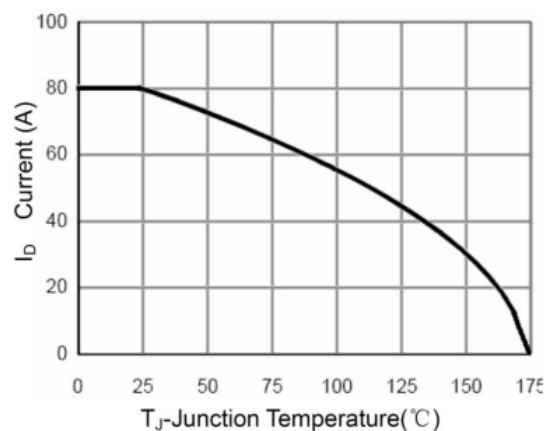
Capacitance vs Vds



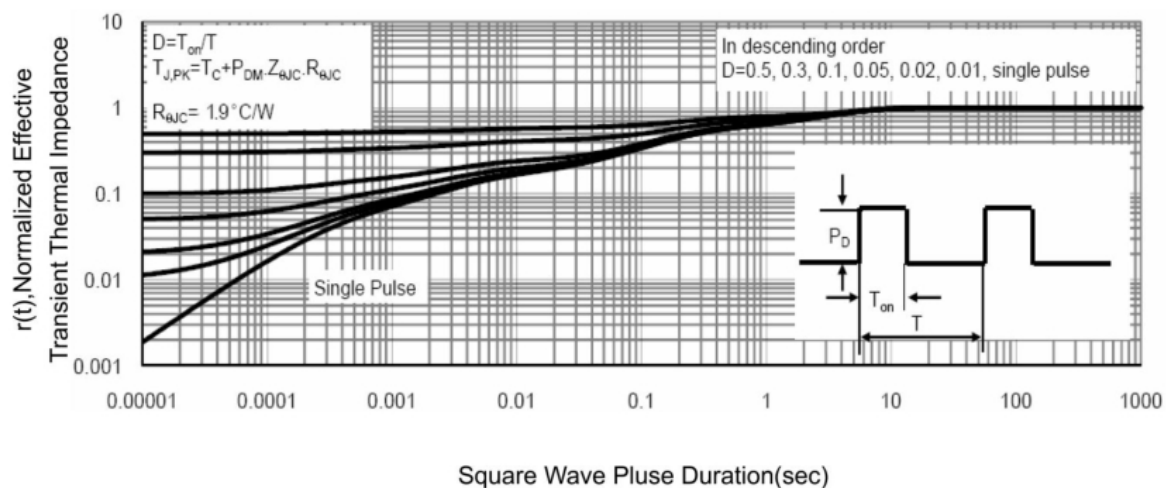
Power De-rating



Safe Operation Area

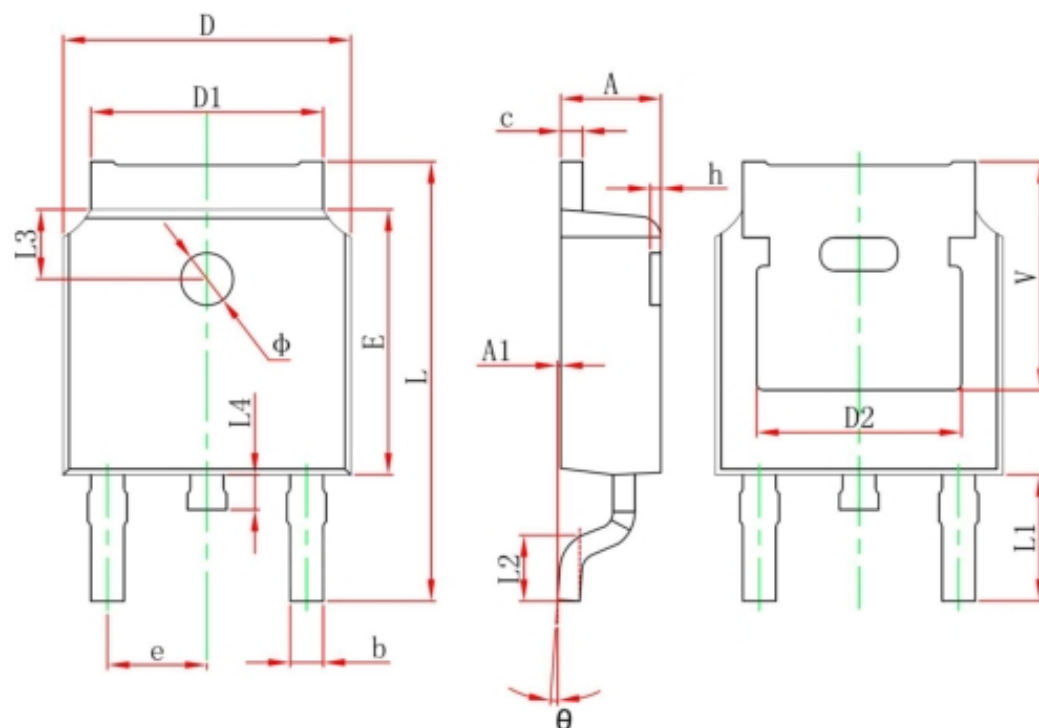


ID Current- Junction Temperature



Normalized Maximum Transient Thermal Impedance

TO-252 Package Information



Symbol	Dimensions in Millimeters		Dimensions in Inches	
	Min.	Max.	Min.	Max.
A	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.660	0.860	0.026	0.034
c	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D1	5.100	5.460	0.201	0.215
D2	4.830 REF.		0.190 REF.	
E	6.000	6.200	0.236	0.244
e	2.186	2.386	0.086	0.094
L	9.800	10.400	0.386	0.409
L1	2.900 REF.		0.114 REF.	
L2	1.400	1.700	0.055	0.067
L3	1.600 REF.		0.063 REF.	
L4	0.600	1.000	0.024	0.039
Φ	1.100	1.300	0.043	0.051
θ	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5.350 REF.		0.211 REF.	